Notice of References Cited Application/Control No. 10/815,843 Examiner A. Sefer Applicant(s)/Patent Under Reexamination AHN ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,678,018	01-2004	Park et al.	349/43
	В	US-2002/0067455	06-2002	Komatsu, Hiroshi	349/141
	С	US-6,531,346	03-2003	Kim, lk Soo	438/149
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 03/001606	01-2003	PCT	Byun et al	
	0	WO 03/036374	05-2003	PCT	Lee et al	
	Р	JP 2003-195784	07-2003	Japan	Chiyabara et al.	
	Q					
	R					
	s					
	T					

NON-PATENT DOCUMENTS

*		• Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	×							

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.